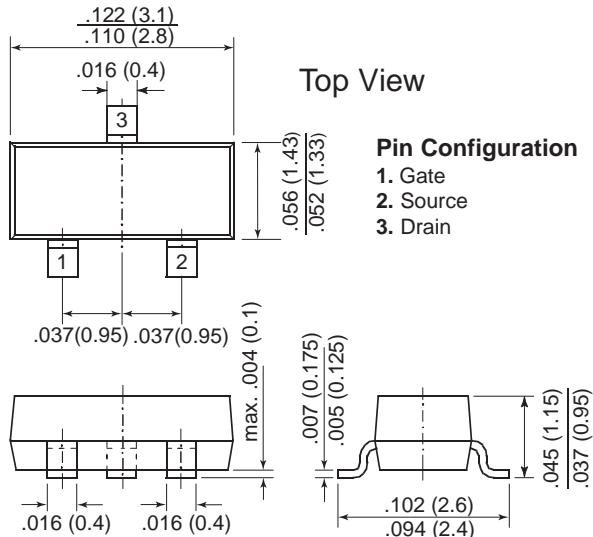
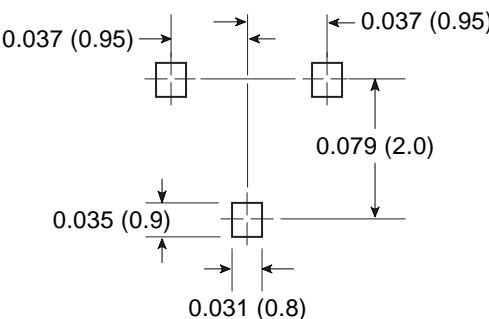



TO-263AB (SOT-23)

Mounting Pad Layout


Features

- High input impedance
- High-speed switching
- No minority carrier storage time
- CMOS logic compatible input
- No thermal runaway
- No secondary breakdown

Mechanical Data

Case: SOT-23 Plastic Package

Weight: approx. 0.008g

Packaging Codes/Options:

E8/10K per 13" reel (8mm tape), 30K/box
E9/3K per 7" reel (8mm tape), 30K/box

Maximum Ratings and Thermal Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DSS}	60	V
Drain-Gate Voltage	V_{DGS}	60	V
Gate-Source-Voltage (pulsed)	V_{GS}	± 20	V
Drain Current (continuous)	I_D	250	mA
Power Dissipation at $T_C = 50^\circ\text{C}$	P_{tot}	0.310 ⁽¹⁾	W
Thermal Resistance Junction to Substrate Backside	$R_{\theta SB}$	320 ⁽¹⁾	$^\circ\text{C}/\text{W}$
Thermal Resistance Junction to Ambiant Air	$R_{\theta JA}$	450 ⁽¹⁾	$^\circ\text{C}/\text{W}$
Junction Temperature	T_j	150	$^\circ\text{C}$
Storage Temperature Range	T_s	-55 to +150	$^\circ\text{C}$

Note:

(1) Ceramic Substrate 0.7mm; 2.5cm² area.

DMOS Transistors (N-Channel)
Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$I_D = 100\mu\text{A}, V_{GS} = 0$	60	90	—	V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{GS} = V_{DS}, I_D = 1\text{mA}$	—	2	2.5	
Gate-Body Leakage Current	I_{GSS}	$V_{GS} = 15\text{V}, V_{DS} = 0\text{V}$	—	—	10	nA
Drain Cutoff Current	I_{DSS}	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}$	—	—	0.5	μA
Drain-Source On-State Resistance	$R_{DS(\text{on})}$	$V_{GS} = 10\text{V}, I_D = 500\text{mA}$	—	5	7.5	Ω
Forward Transconductance	g_m	$V_{DS} = 10\text{V}, I_D = 200\text{mA}, f = 1\text{MHz}$	—	200	—	mS
Input Capacitance	C_{iss}	$V_{DS} = 10\text{V}, V_{GS} = 0, f = 1\text{MHz}$	—	60	—	pF
Turn-On Time	t_{on}	$V_{GS} = 10\text{V}, V_{DS} = 10\text{V}$	—	5	—	ns
Turn-Off Time	t_{off}		—	25	—	ns

Note:

(1)Device on fiberglass substrate, see layout

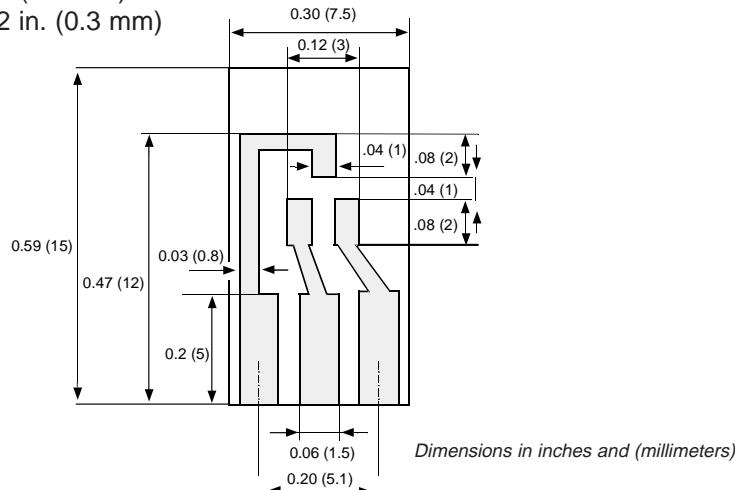
Inverse Diode

Parameter	Symbol	Test Condition	Value	Unit
Max. Forward Current (continuous)	I_F	$T_{\text{amb}} = 25^\circ\text{C}$	0.3	A
Forward Voltage Drop (typ.)	V_F	$V_{GS} = 0\text{V}, I_F = 0.3\text{A}$ $T_J = 25^\circ\text{C}$	0.85	V

Layout for R_{thJA} test

Thickness: Fiberglass 0.059 in. (1.5 mm)

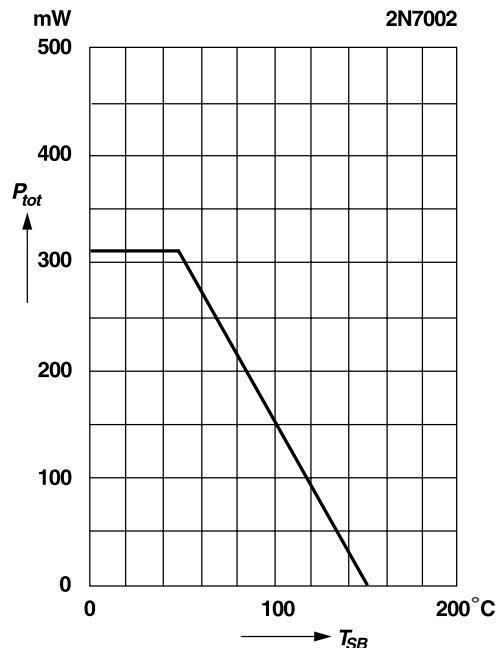
Copper leads 0.012 in. (0.3 mm)



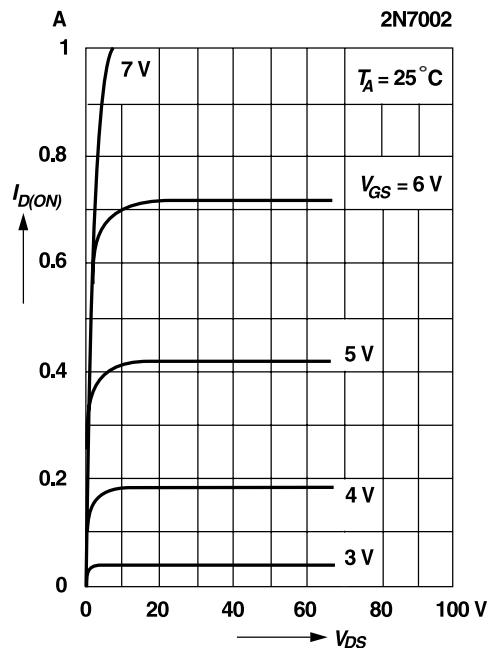
DMOS Transistors (N-Channel)

Ratings and Characteristic Curves ($T_A = 25^\circ\text{C}$ unless otherwise noted)

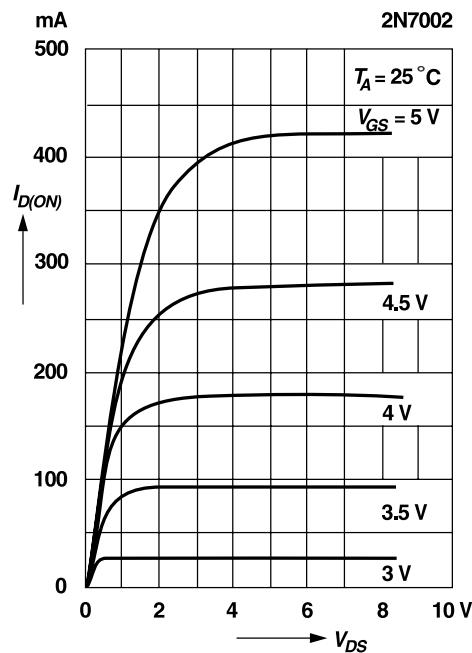
Admissible power dissipation
versus temperature of substrate backside
Device on fiberglass substrate, see layout



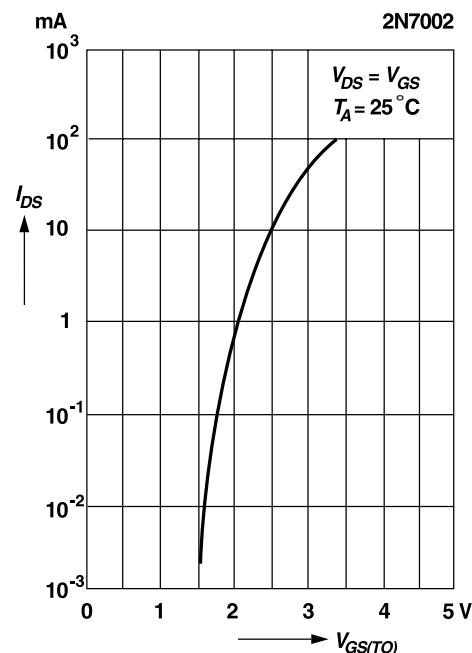
Output characteristics
Pulse test width 80 ms; pulse duty factor 1%.



Saturation characteristics
Pulse test width 80 ms; pulse duty factor 1%.



Drain-source current
versus gate threshold voltage

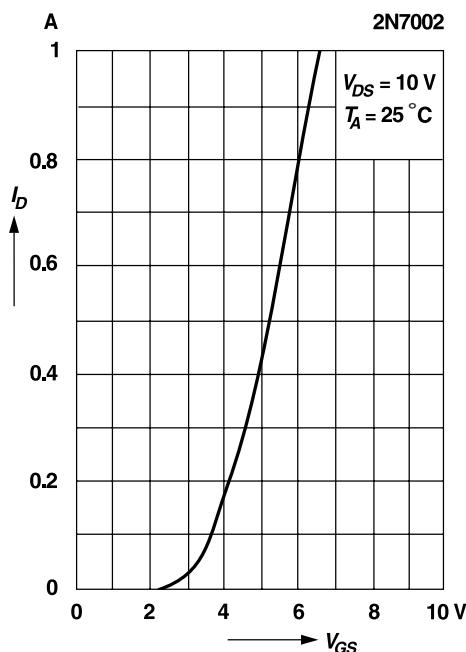


DMOS Transistors (N-Channel)

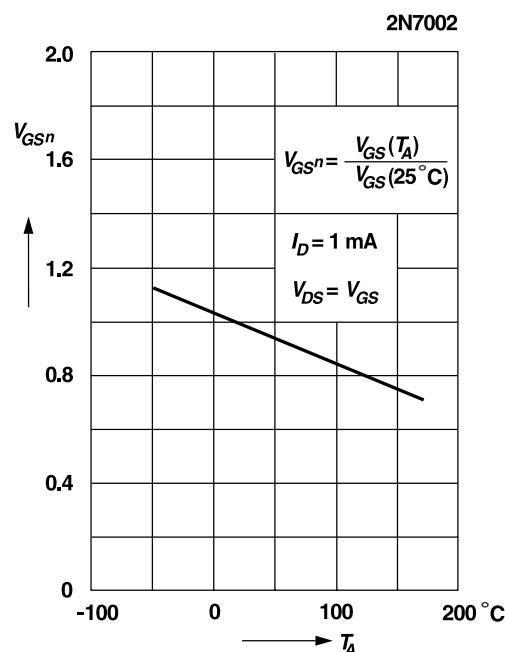
Ratings and Characteristic Curves (TA = 25°C unless otherwise noted)

**Drain current
versus gate-source voltage**

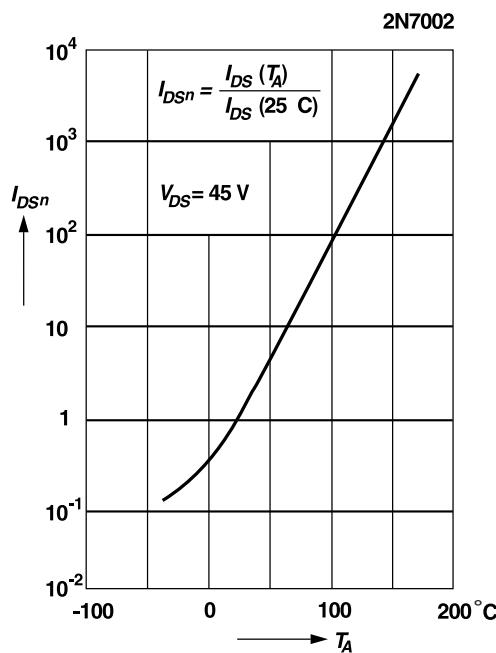
Pulse test width 80 ms; pulse duty factor 1%.



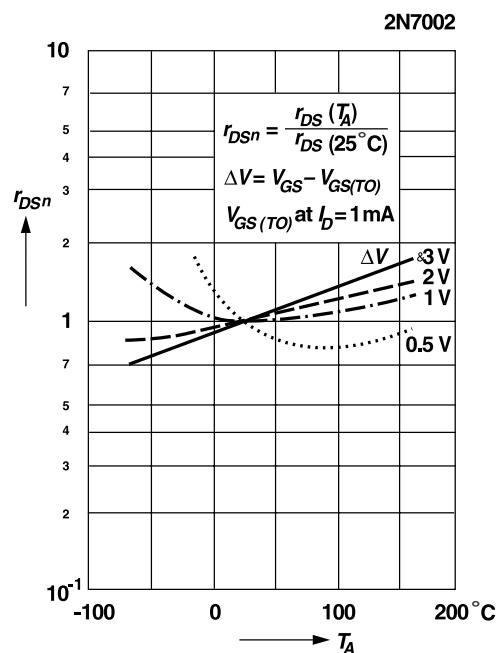
**Normalized gate-source voltage
versus temperature**



**Normalized drain-source current
versus temperature**



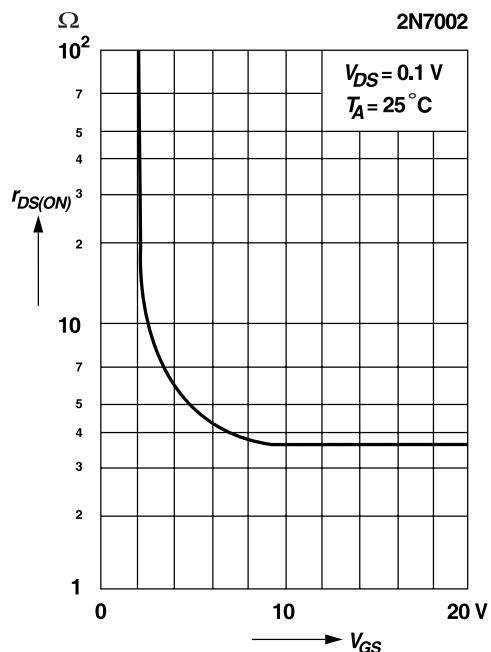
**Normalized drain-source resistance
versus temperature**



DMOS Transistors (N-Channel)

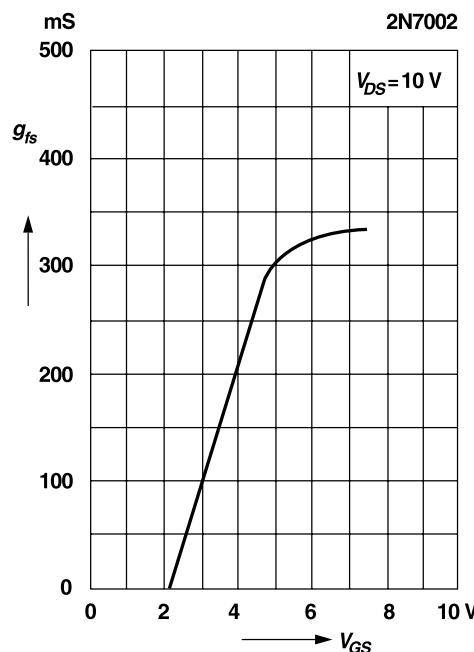
Ratings and Characteristic Curves ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Drain-source resistance
versus gate-source voltage



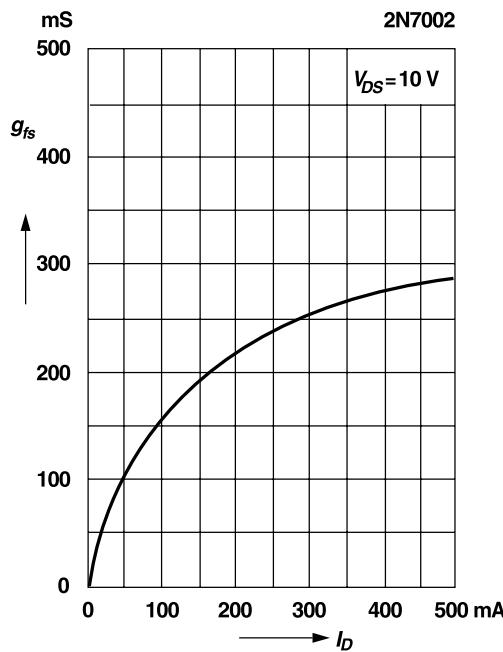
Transconductance
versus gate-source voltage

Pulse test width 80 ms; pulse duty factor 1%



Transconductance
versus drain current

Pulse test width 80 ms; pulse duty factor 1%



Capacitance
versus drain-source voltage

